

Low Noise, Precision Instrumentation Amplifier

AMPN1*

FEATURES

Low Offset Voltage: 50 μV Max

Very Low Offset Voltage Drift: $0.3 \mu V/^{\circ}C$ Max Low Noise: $0.12 \mu V$ p-p (0.1 Hz to 10 Hz) Excellent Output Drive: $\pm 10 V$ at $\pm 50 mA$

Capacitive Load Stability: to 1 μF

Gain Range: 0.1 to 10,000

Excellent Linearity: 16-Bit at G = 1000 High CMR: 125 dB min (G = 1000) Low Bias Current: 4 nA Max

May Be Configured as a Precision Op Amp

Output-Stage Thermal Shutdown

Available in Die Form

GENERAL DESCRIPTION

The AMP01 is a monolithic instrumentation amplifier designed for high-precision data acquisition and instrumentation applications. The design combines the conventional features of an instrumentation amplifier with a high current output stage. The output remains stable with high capacitance loads (1 μF), a unique ability for an instrumentation amplifier. Consequently, the AMP01 can amplify low level signals for transmission through long cables without requiring an output buffer. The output stage may be configured as a voltage or current generator.

Input offset voltage is very low (20 μV), which generally eliminates the external null potentiometer. Temperature changes have minimal effect on offset; TCV_{IOS} is typically 0.15 $\mu V/^{\circ}C$. Excellent low-frequency noise performance is achieved with a minimal compromise on input protection. Bias current is very low, less than 10 nA over the military temperature range. High common-mode rejection of 130 dB, 16-bit linearity at a gain of 1000, and 50 mA peak output current are achievable simultaneously. This combination takes the instrumentation amplifier one step further towards the ideal amplifier.

AC performance complements the superb dc specifications. The AMP01 slews at 4.5 V/ μ s into capacitive loads of up to 15 nF, settles in 50 μ s to 0.01% at a gain of 1000, and boasts a healthy 26 MHz gain-bandwidth product. These features make the AMP01 ideal for high speed data acquisition systems.

Gain is set by the ratio of two external resistors over a range of 0.1 to 10,000. A very low gain temperature coefficient of 10 ppm/°C is achievable over the whole gain range. Output voltage swing is guaranteed with three load resistances; 50 Ω , 500 Ω , and 2 k Ω . Loaded with 500 Ω , the output delivers ± 13.0 V minimum. A thermal shutdown circuit prevents destruction of the output transistors during overload conditions.

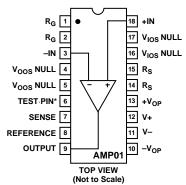
The AMP01 can also be configured as a high performance operational amplifier. In many applications, the AMP01 can be used in place of op amp/power-buffer combinations.

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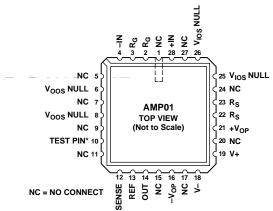
PIN CONFIGURATIONS

18-Lead Cerdip



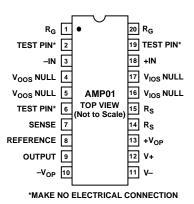
*MAKE NO ELECTRICAL CONNECTION

AMP01 BTC/883 28-Terminal LCC



*MAKE NO ELECTRICAL CONNECTION

20-Lead SOIC



*Protected under U.S. Patent Numbers 4,471,321 and 4,503,381.

AMP01-SPECIFICATIONS

ELECTRICAL CHARACTERISTICS (@ $V_S = \pm 15$ V, $R_S = 10$ k Ω , $R_L = 2$ k Ω , $T_A = +25^{\circ}$ C, unless otherwise noted)

			A	AMP01A		AMP01B			
Parameter	Symbol	Conditions	Min	Typ	Max	Min	Typ	Max	Units
OFFSET VOLTAGE Input Offset Voltage	V _{IOS}	$T_A = +25^{\circ}C$ -55°C \le T_A \le +125°C		20 40	50 80		40 60	100 150	μV μV
Input Offset Voltage Drift Output Offset Voltage	TCV _{IOS} V _{OOS}	$ \begin{array}{l} -55^{\circ}C \le T_{A} \le +125^{\circ}C \\ T_{A} = +25^{\circ}C \\ -55^{\circ}C \le T_{A} \le +125^{\circ}C \end{array} $		0.15 1 3	0.3 3 6		0.3 2 6	1.0 6 10	μV/°C mV mV
Output Offset Voltage Drift	TCV _{oos}	$R_G = \infty$ $-55^{\circ}C \le T_A \le +125^{\circ}C$		20	50		50	120	μV/°C
Offset Referred to Input vs. Positive Supply V+ = +5 V to +15 V	PSR	G = 1000 G = 100 G = 10 G = 1	120 110 95 75	130 130 110 90		110 100 90 70	120 120 100 80		dB dB dB dB
Offset Referred to Input vs. Negative Supply V- = -5 V to -15 V	PSR	$-55^{\circ}C \le T_A \le +125^{\circ}C$ G = 1000 G = 100 G = 1 G = 1 G = 1000 G = 100 G = 10 G = 1	120 110 95 75 105 90 70 50	130 130 110 90 125 105 85 65		110 100 90 70 105 90 70 50	120 120 100 80 115 95 75 60		dB dB dB dB dB dB dB
		$-55^{\circ}C \le T_A \le +125^{\circ}C$ G = 1000 G = 100 G = 10 G = 1	105 90 70 50	125 105 85 85		105 90 70 50	115 95 75 60		dB dB dB dB
Input Offset Voltage Trim Range Output Offset Voltage Trim		$\overline{V}_S = \pm 4.5 \text{ V to } \pm 18 \text{ V}^T$		±6			±6		mV
Range		$V_S = \pm 4.5 \text{ V to } \pm 18 \text{ V}^1$		±100			±100		mV
INPUT CURRENT Input Bias Current	I_{B}	$T_A = +25^{\circ}C$ -55°C \le T_A \le +125°C		1 4	4 10		2 6	6 15	nA nA
Input Bias Current Drift Input Offset Current	TCI_B I_{OS}	$ \begin{array}{l} -55^{\circ}C \le T_{A} \le +125^{\circ}C \\ T_{A} = +25^{\circ}C \\ -55^{\circ}C \le T_{A} \le +125^{\circ}C \end{array} $		40 0.2 0.5	1.0 3.0		50 0.5 1.0	2.0 6.0	pA/°C nA nA
Input Offset Current Drift	TCI _{OS}	$-55^{\circ}\text{C} \le \text{T}_{\text{A}} \le +125^{\circ}\text{C}$		3			5		pA/°C
INPUT Input Resistance	R _{IN}	Differential, $G = 1000$ Differential, $G \le 100$ Common Mode, $G = 1000$		1 10 20			1 10 20		$G\Omega$ $G\Omega$
Input Voltage Range	IVR	$T_A = +25^{\circ}C^2$ -55°C \leq T_A \leq +125°C	±10.5 ±10.0			±10.5 ±10.0			V V
Common-Mode Rejection	CMR	$V_{CM} = \pm 10 \text{ V}, 1 \text{ k}\Omega$ Source Imbalance G = 1000 G = 100 G = 10 G = 1	125 120 100 85	130 130 120 100		115 110 95 75	125 125 110 90		dB dB dB dB
		$-55^{\circ}\text{C} \le \text{T}_{\text{A}} \le +125^{\circ}\text{C}$ G = 1000 G = 100 G = 10 G = 1	120 115 95 80	125 125 115 95		110 105 90 75	120 120 105 90		dB dB dB dB

NOTES

 $^{^{\}rm I}V_{\rm IOS}$ and $V_{\rm OOS}$ nulling has minimal affect on $TCV_{\rm IOS}$ and $TCV_{\rm OOS}$ respectively.

²Refer to section on common-mode rejection.

Specifications subject to change without notice.

ELECTRICAL CHARACTERISTICS (@ $V_S = \pm 15$ V, $R_S = 10$ k Ω , $R_L = 2$ k Ω , $T_A = +25$ °C, -25°C $\leq T_A \leq +85$ °C for E, F grades, 0°C $\leq T_A \leq +70$ °C for G grade, unless otherwise noted)

			l A	MP01	E	AN	/P01F/	G		
Parameter	Symbol	Conditions	Min	Typ	Max	Min	Typ	Max	Units	
OFFSET VOLTAGE Input Offset Voltage	V _{IOS}	$T_{A} = +25^{\circ}C$ $T_{MIN} \le T_{A} \le T_{MAX}$		20 40	50 80		40 60	100 150	μV μV	
Input Offset Voltage Drift Output Offset Voltage	V_{OOS}	$ T_{MIN} \le T_A \le T_{MAX}^1 $ $ T_A = +25^{\circ}C$ $ T_{MIN} \le T_A \le T_{MAX}$		0.15 1 3	0.3 3 6		0.3 2 6	1.0 6 10	μV/°C mV mV	
Output Offset Voltage Drift	TCV _{oos}	$R_G = \infty^1$ $T_{MIN} \le T_A \le T_{MAX}$		20	100		50	120	μV/°C	
Offset Referred to Input vs. Positive Supply V+ = +5 V to +15 V	PSR	G = 1000 G = 100 G = 10 G = 1	120 110 95 75	130 130 110 90		110 100 90 70	120 120 100 80		dB dB dB dB	
Offset Referred to Input vs. Negative Supply V- = -5 V to -15 V	PSR	$T_{MIN} \le T_A \le T_{MAX}$ G = 1000 G = 100 G = 1 G = 1 G = 1000 G = 100 G = 10 G = 10	120 110 95 75 110 95 75 55	130 130 110 90 125 105 85 65		110 100 90 70 105 90 70 50	120 120 100 80 115 95 75 60		dB dB dB dB dB dB dB	
		$T_{MIN} \le T_A \le T_{MAX}$ G = 1000 G = 100 G = 10 G = 1	110 95 75 55	125 105 85 85		105 90 70 50	115 95 75 60		dB dB dB dB	
Input Offset Voltage Trim Range Output Offset Voltage Trim Range		$V_S = \pm 4.5 \text{ V to } \pm 18 \text{ V}^2$ $V_S = \pm 4.5 \text{ V to } \pm 18 \text{ V}^2$		±6 ±100			±6 ±100		mV mV	
INPUT CURRENT		75 11.5 7 10 210 7							111 1	
Input Bias Current	I_B	$T_{A} = +25^{\circ}C$ $T_{MIN} \le T_{A} \le T_{MAX}$		1 4	4 10		2 6	6 15	mV mV	
Input Bias Current Drift Input Offset Current	I_{OS}			40 0.2 0.5	1.0 3.0		50 0.5 1.0	2.0 6.0	pA/°C mV mV	
Input Offset Current Drift	TCIos	$T_{MIN} \le T_A \le T_{MAX}$		3			5		pA/°C	
INPUT Input Resistance	R _{IN}	Differential, $G = 1000$ Differential, $G \le 100$ Common Mode, $G = 1000$		1 10 20			1 10 20		$G\Omega$ $G\Omega$ $G\Omega$	
Input Voltage Range	IVR	$T_{A} = +25^{\circ}C^{3}$ $T_{MIN} \le T_{A} \le T_{MAX}$	±10.5 ±10.0			±10.5 ±10.0			V V	
Common-Mode Rejection	CMR	$V_{CM} = \pm 10 \text{ V}, 1 \text{ k}\Omega$ Source Imbalance								
		G = 1000 G = 100 G = 10	125 120 100	130 130 120		115 110 95	125 125 110		dB dB dB	
		G = 1	85	100		75	90		dB	
		$T_{MIN} \le T_A \le T_{MAX}$ G = 1000 G = 100 G = 10	120 115 95	125 125 115		110 105 90	120 120 105		dB dB dB	
		G = 1	80	95		75	90		dB	

NOTES

1 Sample tested.

²Vios and Voos nulling has minimal affect on TCV_{IOS} and TCV_{OOS}, respectively. ³Refer to section on common-mode rejection.

Specifications subject to change without notice.

AMP01 $\textbf{ELECTRICAL CHARACTERISTICS} \ (@\ V_S = \pm 15\ V,\ R_S = 10\ k\Omega,\ R_L = 2\ k\Omega,\ T_A = +25^{\circ}C,\ unless\ otherwise\ noted)$

				AMP0	IA/E	A	MP01E	/F/G	
Parameter	Symbol	Conditions	Min	Typ	Max	Min	Typ	Max	Units
GAIN									
Gain Equation Accuracy		$G = \frac{20 \times R_S}{R_G}$		0.3	0.6		0.5	0.8	%
Gain Range Nonlinearity	G	Accuracy Measured from $G = 1$ to 1000 $G = 1000^{1}$	0.1	0.0007	10k ' 0.005	0.1	0.0007	10k 0.005	V/V %
·		$G = 100^{1}$ $G = 10^{1}$ $G = 1^{1}$			0.005 0.005 0.010			0.005 0.007 0.015	% % %
Temperature Coefficient	G_{TC}	$1 \le G \le 1000^{1, 2}$		5	10		5	15	ppm°C
OUTPUT RATING Output Voltage Swing	V _{OUT}	$R_{L} = 2 \text{ k}\Omega$ $R_{L} = 500 \Omega$ $R_{L} = 50 \Omega$ $R_{L} = 2 \text{ k}\Omega \text{ Over Temp.}$ $R_{L} = 500 \Omega^{3}$	±13.0 ±2.5 ±12.0	±13.8 ±13.5 ±4.0 ±13.8 ±13.5		±13.0 ±2.5 ±12.0	±13.8 ±13.5 ±4.0 ±13.8 ±13.5		V V V V
Positive Current Limit Negative Current Limit Capacitive Load Stability		Output-to-Ground Short Output-to-Ground Short $1 \le G \le 1000$	60 60	100 90	120 120	60 60	100 90	120 120	mA mA
Thermal Shutdown Temperature		No Oscillations ¹ Junction Temperature	0.1	1 165		0.1	1 165		μF °C
NOISE Voltage Density, RTI	e _n	f _O = 1 kHz G = 1000		=			5		nV/√ Hz
Noise Current Density, RTI Input Noise Voltage	$\begin{array}{c} e_n \\ e_n \\ e_n \\ e_n \\ i_n \\ e_n \ p-p \\ e_n \ p-p \\ e_n \ p-p \end{array}$	G = 1000 G = 100 G = 10 G = 1 f ₀ = 1 kHz, G = 1000 0.1 Hz to 10 Hz G = 1000 G = 100		5 10 59 540 0.15 0.12 0.16			5 10 59 540 0.15 0.12 0.16		$\begin{array}{c} \text{nV} \backslash \overline{\text{Hz}} \\ \text{nV} / \sqrt{\overline{\text{Hz}}} \\ \text{nV} / \sqrt{\overline{\text{Hz}}} \\ \text{nV} / \sqrt{\overline{\text{Hz}}} \\ \text{pA} / \sqrt{\overline{\text{Hz}}} \\ \text{pV p-p} \\ \text{\muV p-p} \\ \text{\muV p-p} \end{array}$
Input Noise Current	$\begin{array}{c} e_n p - p \\ e_n p - p \\ i_n p - p \end{array}$	G = 10 G = 1 0.1 Hz to 10 Hz, G = 1000		1.4 13 2			1.4 13 2		μV p-p μV p-p pA p-p
DYNAMIC RESPONSE Small-Signal	-n F P	G = 1		570			570		kHz
Bandwidth (–3 dB)	BW	G = 10 G = 100 G = 1000		100 82 26			100 82 26		kHz kHz kHz
Slew Rate Settling Time	SR t _S	G = 10 To 0.01%, 20 V step G = 1	3.5	4.5 12		3.0	4.5 12		V/μs μs
		G = 10 G = 100 G = 1000		13 15 50			13 15 50		μs μs μs

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²Gain tempco does not include the effects of gain and scale resistor tempco match. ³–55°C \leq T_A \leq +125°C for A/B grades, -25°C \leq T_A \leq +85°C for E/F grades, 0°C \leq T_A \leq 70°C for G grades.

Specifications subject to change without notice.

ELECTRICAL CHARACTERISTICS (@ $V_S = \pm 15$ V, $R_S = 10$ k Ω , $R_L = 2$ k Ω , $T_A = +25$ °C, unless otherwise noted)

			AN	AP 01A	/E	AM	P01B/F	F/G	
Parameter	Symbol	Conditions	Min	Typ	Max	Min	Typ	Max	Units
SENSE INPUT Input Resistance Input Current Voltage Range	$egin{array}{c} R_{\mathrm{IN}} \ I_{\mathrm{IN}} \end{array}$	Referenced to V– (Note 1)	35 -10.5	50 280	65 +15	35 -10.5	50 280	65 +15	kΩ μΑ V
REFERENCE INPUT Input Resistance Input Current Voltage Range Gain to Output	R _{IN} I _{IN}	Referenced to V– (Note 1)	35 -10.5	50 280	65 +15	35 -10.5	50 280	65 +15	kΩ μΑ V V/V
POWER SUPPLY $-25^{\circ}\text{C} \le \text{T}_{\text{A}} \le +85^{\circ}\text{C}$ for E/F Grades, $-55^{\circ}\text{C} \le \text{T}_{\text{A}} \le +125^{\circ}\text{C}$ for A/B Grades									
Supply Voltage Range	$egin{array}{c} V_{ m S} \ V_{ m S} \end{array}$	+V linked to +V _{OP} -V linked to -V _{OP}	±4.5 ±4.5		±18 ±18	±4.5 ±4.5		±18 ±18	V V
Quiescent Current	$egin{array}{c} I_Q \ I_Q \end{array}$	+V linked to +V _{OP} -V linked to -V _{OP}		3.0 3.4	4.8 4.8		3.0 3.4	4.8 4.8	mA mA

NOTE

¹Guaranteed by design.

Specifications subject to change without notice.

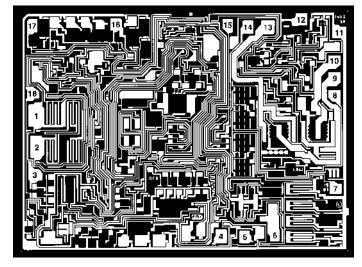
ORDERING GUIDE

Model	Temperature Range	Package Description	Package Option
AMP01AX	−55°C to +125°C	18-Lead Cerdip	Q-18
AMP01AX/883C	−55°C to +125°C	18-Lead Cerdip	Q-18
AMP01BTC/883C	−55°C to +125°C	28-Terminal LCC	E-28A
AMP01BX	−55°C to +125°C	18-Lead Cerdip	Q-18
AMP01BX/883C	−55°C to +125°C	18-Lead Cerdip	Q-18
AMP01EX	−25°C to +85°C	18-Lead Cerdip	Q-18
AMP01FX	−25°C to +85°C	18-Lead Cerdip	Q-18
AMP01GBC		Die	-
AMP01GS	0°C to +70°C	20-Lead SOIC	R-20
AMP01GS-REEL	0°C to +70°C	13" Tape and Reel	R-20
AMP01NBC		Die	
5962-8863001VA*	−55°C to +125°C	18-Lead Cerdip	Q-18
5962-88630023A*	−55°C to +125°C	28-Terminal LCC	E-28A
5962-8863002VA*	−55°C to +125°C	18-Lead Cerdip	Q-18

^{*}Standard military drawing available.

DICE CHARACTERISTICS

Die Size 0.111×0.149 inch, 16,539 sq. mils $(2.82 \times 3.78$ mm, 10.67 sq. mm)



1. R_G 10. V- (OUTPUT)
2. R_G 11. V3. -INPUT 12. V+
4. V_{OOS} NULL 13. V+ (OUTPUT)
5. V_{OOS} NULL 14. R_S
15. R_S
16. V_{IOS} NULL 17. V_{IOS} NULL
9. OUTPUT 18. +INPUT

* MAKE NO ELECTRICAL CONNECTION

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Parameter	Symbol	Conditions	AMP01NBC Limit	AMP01GBC Limit	Units
Input Offset Voltage	V _{IOS}		60	120	μV max
Output Offset Voltage	Voos		4	8	mV max
Offset Referred to Input	PSR	V+ = +5 V to +15 V			dB min
vs. Positive Supply		G = 1000	120	110	dB min
		G = 100	110	100	dB min
		G = 10	95	90	dB min
		G = 1	75	70	dB min
Offset Referred to Input	PSR	V = -5 V to -15 V			dB min
vs. Negative Supply		G = 1000	105	105	dB min
		G = 100	90	90	dB min
		G = 10	70	70	dB min
		G = 1	50	50	dB min
Input Bias Current	I_{B}		4	8	nA max
Input Offset Current	I_{OS}		1	3	nA max
Input Voltage Range	IVR	Guaranteed by CMR Tests	± 10	±10	V min
Common Mode Rejection	CMR	$V_{CM} = \pm 10 \text{ V}$			dB min
		G = 1000	125	115	dB min
		G = 100	120	110	dB min
		G = 10	100	95	dB min
		G = 1	85	75	dB min
Gain Equation Accuracy		$G = \frac{20 \times R_S}{R_G}$	0.6	0.8	% max
Output Voltage Swing	V _{OUT}	$R_L = 2 k\Omega$	±13	±13	V min
	V_{OUT}	$R_{\rm L} = 500 \ \Omega$	±13	±13	V min
	V_{OUT}	$R_L = 50 \Omega$	±2.5	±2.5	V min
Output Current Limit		Output to Ground Short	± 60	±60	mA min
Output Current Limit		Output to Ground Short_	±120	±120	mA max
Quiescent Current	I_Q	+V Linked to +V _{OP}	4.8	4.8	mA max
		–V Linked to –V _{OP}	4.8	4.8	mA max

NOTE

Electrical tests are performed at wafer probe to the limits shown. Due to variations in assembly methods and normal yield loss, yield after packaging is not guaranteed for standard product dice. Consult factory to negotiate specifications based on dice lot qualification through sample lot assembly and testing.

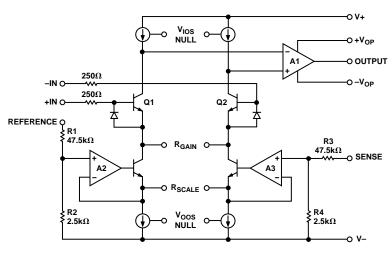


Figure 1. Simplified Schematic

CAUTION

ESD (electrostatic discharge) sensitive device. Electrostatic charges as high as 4000 V readily accumulate on the human body and test equipment and can discharge without detection. Although the AMP01 features proprietary ESD protection circuitry, permanent damage may occur on devices subjected to high energy electrostatic discharges. Therefore, proper ESD precautions are recommended to avoid performance degradation or loss of functionality.



ELECTRICAL CHARACTERISTICS (@ $V_S = \pm 15$ V, $R_S = 10$ k Ω , $R_L = 2$ k Ω , $T_A = +25$ °C, unless otherwise noted)

Parameter	Symbol	Conditions	AMP01NBC Typical	AMP01GBC Typical	Units
Input Offset Voltage Drift	TCV _{IOS}		0.15	0.30	μV/°C
Output Offset Voltage Drift	TCVoos	$R_G = \infty$	20	50	μV/°C
Input Bias Current Drift	TCI_B		40	50	pA/°C
Input Offset Current Drift	TCIos		3	5	pA/°C
Nonlinearity		G = 1000	0.0007	0.0007	%
Voltage Noise Density	e _n	G = 1000			
		$f_O = 1 \text{ kHz}$	5	5	nV/\sqrt{Hz}
Current Noise Density	i _n	G = 1000			
		$f_O = 1 \text{ kHz}$	0.15	0.15	pA/\sqrt{Hz}
Voltage Noise	e _n p-p	G = 1000			
		0.1 Hz to 10 Hz	0.12	0.12	μV p-p
Current Noise	i _n p-p	G = 1000	2	2	pA p-p
		0.1 Hz to 10 Hz			
Small-Signal Bandwidth (-3 dB)	BW	G = 1000	26	26	kHz
Slew Rate	SR	G = 10	4.5	4.5	V/µs
Settling Time	t_S	To 0.01%, 20 V Step			
		G = 1000	50	50	μs

NOTE

Electrical tests are performed at wafer probe to the limits shown. Due to variations in assembly methods and normal yield loss, yield after packaging is not guaranteed for standard product dice. Consult factory to negotiate specifications based on dice lot qualification through sample lot assembly and testing.

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AMP01—Typical Performance Characteristics

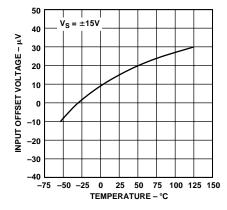


Figure 2. Input Offset Voltage vs. Temperature

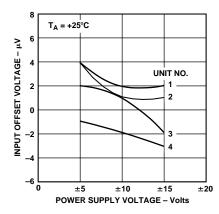


Figure 3. Input Offset Voltage vs. Supply Voltage

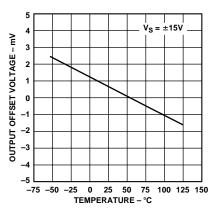


Figure 4. Output Offset Voltage vs. Temperature

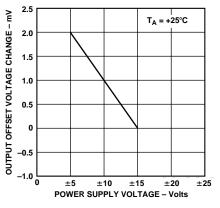


Figure 5. Output Offset Voltage Change vs. Supply Voltage

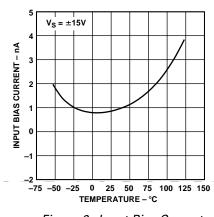


Figure 6. Input Bias Current vs. Temperature

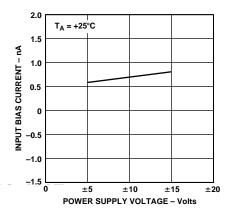


Figure 7. Input Bias Current vs. Supply Voltage

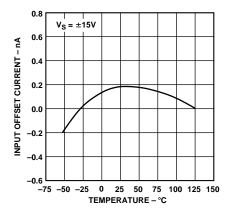


Figure 8. Input Offset Current vs. Temperature

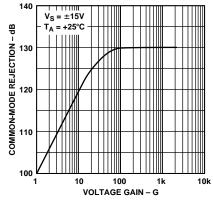


Figure 9. Common-Mode Rejection vs. Voltage Gain

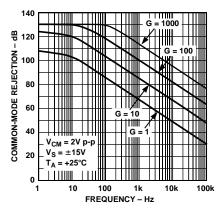


Figure 10. Common-Mode Rejection vs. Frequency

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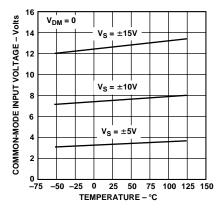


Figure 11. Common-Mode Voltage Range vs. Temperature

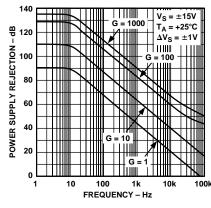


Figure 12. Positive PSR vs. Frequency

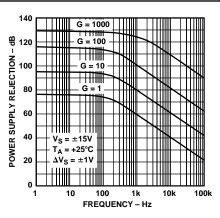


Figure 13. Negative PSR vs. Frequency

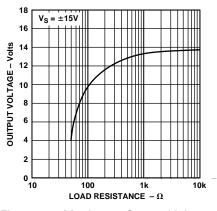


Figure 14. Maximum Output Voltage vs. Load Resistance

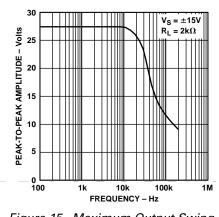


Figure 15. Maximum Output Swing vs. Frequency

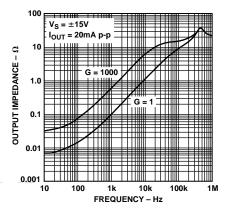


Figure 16. Closed-Loop Output Impedance vs. Frequency

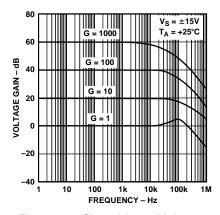


Figure 17. Closed-Loop Voltage Gain vs. Frequency

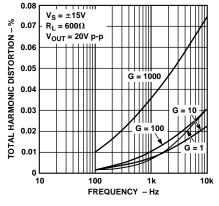


Figure 18. Total Harmonic Distortion vs. Frequency

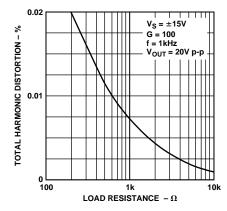


Figure 19. Total Harmonic Distortion vs. Load Resistance

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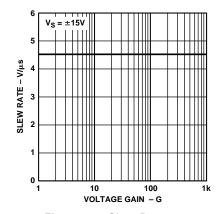


Figure 20. Slew Rate vs. Voltage Gain

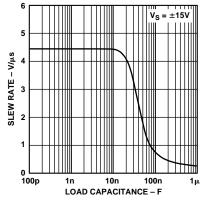


Figure 21. Slew Rate vs. Load Capacitance

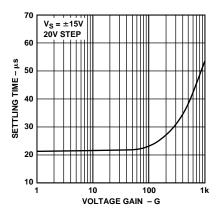


Figure 22. Settling Time to 0.01% vs. Voltage Gain

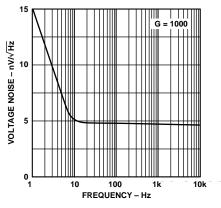


Figure 23. Voltage Noise Density vs. Frequency

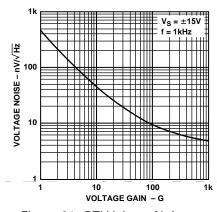


Figure 24. RTI Voltage Noise Density vs. Gain

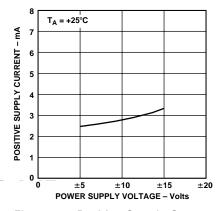


Figure 25. Positive Supply Current vs. Supply Voltage

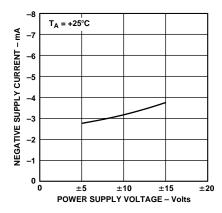


Figure 26. Negative Supply Current vs. Supply Voltage

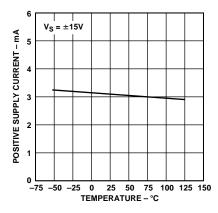


Figure 27. Positive Supply Current vs. Temperature

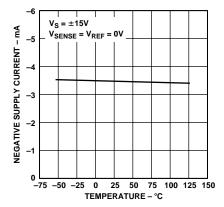


Figure 28. Negative Supply Current vs. Temperature

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INPUT AND OUTPUT OFFSET VOLTAGES

Instrumentation amplifiers have independent offset voltages associated with the input and output stages. While the initial offsets may be adjusted to zero, temperature variations will cause shifts in offsets. Systems with auto-zero can correct for offset errors, so initial adjustment would be unnecessary. However, many high-gain applications don't have auto zero. For these applications, both offsets can be nulled, which has minimal effect on TCV_{IOS} and TCV_{OOS}

The input offset component is directly multiplied by the amplifier gain, whereas output offset is independent of gain. Therefore, at low gain, output-offset errors dominate, while at high gain, input-offset errors dominate. Overall offset voltage, V_{OS} , referred to the output (RTO) is calculated as follows;

$$V_{OS}(RTO) = (V_{IOS} \times G) + V_{OOS} \tag{1}$$

where $V_{\rm IOS}$ and $V_{\rm OOS}$ are the input and output offset voltage specifications and G is the amplifier gain. Input offset nulling alone is recommended with amplifiers having fixed gain above 50. Output offset nulling alone is recommended when gain is fixed at 50 or below.

In applications requiring both initial offsets to be nulled, the input offset is nulled first by short-circuiting R_G , then the output offset is nulled with the short removed.

The overall offset voltage drift TCV_{OS}, referred to the output, is a combination of input and output drift specifications. Input offset voltage drift is multiplied by the amplifier gain, G, and summed with the output offset drift;

$$TCV_{OS}(RTO) = (TCV_{IOS} \times G) + TCV_{OOS}$$
 (2)

where TCV_{IOS} is the input offset voltage drift, and TCV_{OOS} is the output offset voltage specification. Frequently, the amplifier drift is referred back to the input (RTI), which is then equivalent to an input signal change;

$$TCV_{OS}(RTI) = TCV_{IOS} \frac{TCV_{OOS}}{G}$$
 (3)

For example, the maximum input-referred drift of an AMP01 EX set to G = 1000 becomes;

$$TCV_{OS}\left(RTI\right)=0.3~\mu V/^{\circ}\text{C}+\frac{100\,\mu V/^{\circ}C}{1000}=0.4~\mu V/^{\circ}\text{C}~max$$

INPUT BIAS AND OFFSET CURRENTS

Input transistor bias currents are additional error sources that can degrade the input signal. Bias currents flowing through the signal source resistance appear as an additional offset voltage. Equal source resistance on both inputs of an IA will minimize offset changes due to bias current variations with signal voltage and temperature. However, the difference between the two bias currents, the input offset current, produces a nontrimmable error. The magnitude of the error is the offset current times the source resistance.

A current path must always be provided between the differential inputs and analog ground to ensure correct amplifier operation. Floating inputs, such as thermocouples, should be grounded close to the signal source for best common-mode rejection.

GAIN

The AMP01 uses two external resistors for setting voltage gain over the range 0.1 to 10,000. The magnitudes of the scale resistor, R_S , and gain-set resistor, R_G , are related by the formula: $G = 20 \times R_S/R_G$, where G is the selected voltage gain (refer to Figure 29).

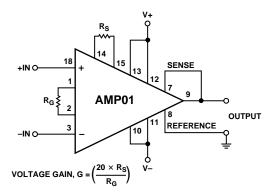


Figure 29. Basic AMP01 Connections for Gains 0.1 to 10,000

The magnitude of R_s affects linearity and output referred errors. Circuit performance is characterized using $R_S = 10 \text{ k}\Omega$ when operating on ± 15 volt supplies and driving a ± 10 volt output. R_S may be reduced to 5 k Ω in many applications particularly when operating on ± 5 volt supplies or if the output voltage swing is limited to ± 5 volts. Bandwidth is improved with $R_S = 5 \text{ k}\Omega$ and this also increases common-mode rejection by approximately 6 dB at low gain. Lowering the value below 5 k Ω can cause instability in some circuit configurations and usually has no advantage. High voltage gains between two and ten thousand would require very low values of R_G . For $R_S = 10 \text{ k}\Omega$ and $A_V = 2000$ we get $R_G = 100 \Omega$; this value is the practical lower limit for R_G . Below 100 Ω , mismatch of wirebond and resistor temperature coefficients will introduce significant gain tempco errors. Therefore, for gains above 2,000, R_G should be kept constant at 100 Ω and R_S increased. The maximum gain of 10,000 is obtained with R_S set to 50 k Ω .

Metal-film or wirewound resistors are recommended for best results. The absolute values and TCs are not too important, only the ratiometric parameters.

AC amplifiers require good gain stability with temperature and time, but dc performance is unimportant. Therefore, low cost metal-film types with TCs of 50 ppm/°C are usually adequate for $R_{\rm S}$ and $R_{\rm G}$. Realizing the full potential of the AMP01's offset voltage and gain stability requires precision metal-film or wirewound resistors. Achieving a 15 ppm/°C gain tempco at all gains requires $R_{\rm S}$ and $R_{\rm G}$ temperature coefficient matching to 5 ppm/°C or better.

REV. D –11–

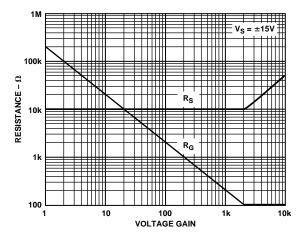


Figure 30. R_G and R_S Selection

Gain accuracy is determined by the ratio accuracy of R_S and R_G combined with the gain equation error of the AMP01 (0.6% max for A/E grades).

All instrumentation amplifiers require attention to layout so thermocouple effects are minimized. Thermocouples formed between copper and dissimilar metals can easily destroy the TCVOS performance of the AMP01 which is typically 0.15 $\mu\text{V}/^{\circ}\text{C}$. Resistors themselves can generate thermoelectric EMF's when mounted parallel to a thermal gradient. "Vishay" resistors are recommended because a maximum value for thermoelectric generation is specified. However, where thermal gradients are low and gain TCs of 20 ppm–50 ppm are sufficient, general-purpose metal-film resistors can be used for R_G and R_S .

COMMON-MODE REJECTION

Ideally, an instrumentation amplifier responds only to the difference between the two input signals and rejects commonmode voltages and noise. In practice, there is a small change in output voltage when both inputs experience the same commonmode voltage change; the ratio of these voltages is called the common-mode gain. Common-mode rejection (CMR) is the logarithm of the ratio of differential-mode gain to commonmode gain, expressed in dB. CMR specifications are normally measured with a full-range input voltage change and a specified source resistance unbalance.

The current-feedback design used in the AMP01 inherently yields high common-mode rejection. Unlike resistive feedback designs, typified by the three-op-amp IA, the CMR is not degraded by small resistances in series with the reference input. A slight, but trimmable, output offset voltage change results from resistance in series with the reference input.

The common-mode input voltage range, CMVR, for linear operation may be calculated from the formula:

$$CMVR = \pm \left(IVR - \frac{|V_{OUT}|}{2G} \right) \tag{4}$$

IVR is the data sheet specification for input voltage range; V_{OUT} is the maximum output signal; G is the chosen voltage gain. For example, at $\pm 25^{\circ}$ C, IVR is specified as ± 10.5 volt minimum with ± 15 volt supplies. Using a ± 10 volt maximum swing output and substituting the figures in (4) simplifies the formula to:

$$CMVR = \pm \left(10.5 - \frac{5}{G}\right) \tag{5}$$

For all gains greater than or equal to 10, CMVR is ± 10 volt minimum; at gains below 10, CMVR is reduced.

ACTIVE GUARD DRIVE

Rejection of common-mode noise and line pick-up can be improved by using shielded cable between the signal source and the IA. Shielding reduces pick-up, but increases input capacitance, which in turn degrades the settling-time for signal changes. Further, any imbalance in the source resistance between the inverting and noninverting inputs, when capacitively loaded, converts the common-mode voltage into a differential voltage. This effect reduces the benefits of shielding. AC common-mode rejection is improved by "bootstrapping" the input cable capacitance to the input signal, a technique called "guard driving." This technique effectively reduces the input capacitance. A single guard-driving signal is adequate at gains above 100 and should be the average value of the two inputs. The value of external gain resistor R_G is split between two resistors R_{G1} and R_{G2}; the center tap provides the required signal to drive the buffer amplifier (Figure 31).

GROUNDING

The majority of instruments and data acquisition systems have separate grounds for analog and digital signals. Analog ground may also be divided into two or more grounds which will be tied together at one point, usually the analog power-supply ground. In addition, the digital and analog grounds may be joined, normally at the analog ground pin on the A-to-D converter. Following this basic grounding practice is essential for good circuit performance (Figure 32).

Mixing grounds causes interactions between digital circuits and the analog signals. Since the ground returns have finite resistance and inductance, hundreds of millivolts can be developed between the system ground and the data acquisition components. Using separate ground returns minimizes the current flow in the sensitive analog return path to the system ground point. Consequently, noisy ground currents from logic gates do not interact with the analog signals.

Inevitably, two or more circuits will be joined together with their grounds at differential potentials. In these situations, the differential input of an instrumentation amplifier, with its high CMR, can accurately transfer analog information from one circuit to another.

SENSE AND REFERENCE TERMINALS

The sense terminal completes the feedback path for the instrumentation amplifier output stage and is normally connected directly to the output. The output signal is specified with respect to the reference terminal, which is normally connected to analog ground.

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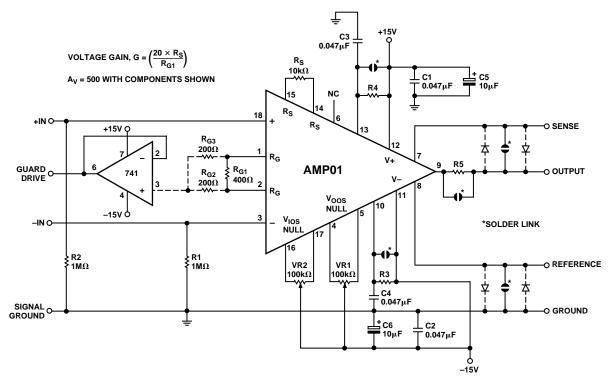


Figure 31. AMP01 Evaluation Circuit Showing Guard-Drive Connection

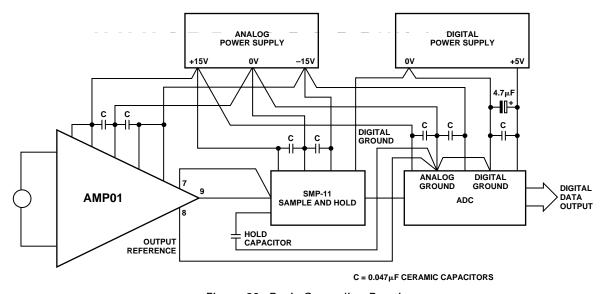


Figure 32. Basic Grounding Practice

REV. D –13–

If heavy output currents are expected and the load is situated some distance from the amplifier, voltage drops due to track or wire resistance will cause errors. Voltage drops are particularly troublesome when driving 50 Ω loads. Under these conditions, the sense and reference terminals can be used to "remote sense" the load as shown in Figure 33. This method of connection puts the I×R drops inside the feedback loop and virtually eliminates the error. An unbalance in the lead resistances from the sense and reference pins does not degrade CMR, but will change the output offset voltage. For example, a large unbalance of 3 Ω will change the output offset by only 1 mV.

DRIVING 50 Ω LOADS

Output currents of 50 mA are guaranteed into loads of up to 50 Ω and 26 mA into 500 Ω . In addition, the output is stable and free from oscillation even with a high load capacitance. The

combination of these unique features in an instrumentation amplifier allows low-level transducer signals to be conditioned and directly transmitted through long cables in voltage or current form. Increased output current brings increased internal dissipation, especially with 50 Ω loads. For this reason, the power-supply connections are split into two pairs; pins 10 and 13 connect to the output stage only and pins 11 and 12 provide power to the input and following stages. Dual supply pins allow dropper resistors to be connected in series with the output stage so excess power is dissipated outside the package. Additional decoupling is necessary between pins 10 and 13 to ground to maintain stability when dropper resistors are used. Figure 34 shows a complete circuit for driving 50 Ω loads.

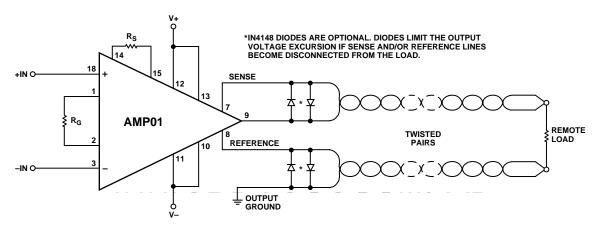


Figure 33. Remote Load Sensing

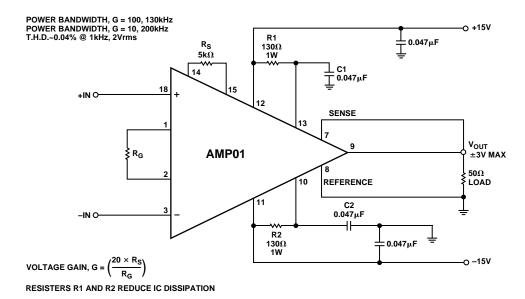


Figure 34. Driving 50 Ω Loads

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HEATSINKING

To maintain high reliability, the die temperature of any IC should be kept as low as practicable, preferably below 100°C. Although most AMP01 application circuits will produce very little internal heat — little more than the quiescent dissipation of 90 mW—some circuits will raise that to several hundred milliwatts (for example, the 4-20 mA current transmitter application, Figure 37). Excessive dissipation will cause thermal shutdown of the output stage thus protecting the device from damage. A heatsink is recommended in power applications to reduce the die temperature.

Several appropriate heatsinks are available; the Thermalloy 6010B is especially easy to use and is inexpensive. Intended for dual-in-line packages, the heatsink may be attached with a cyanoacrylate adhesive. This heatsink reduces the thermal resistance between the junction and ambient environment to approximately 80°C/W. Junction (die) temperature can then be calculated by using the relationship:

$$P_d = \frac{T_J - T_A}{\theta_{JA}}$$

where T_I and T_A are the junction and ambient temperatures respectively, θ_{JA} is the thermal resistance from junction to ambient, and P_d is the device's internal dissipation.

OVERVOLTAGE PROTECTION

Instrumentation amplifiers invariably sit at the front end of instrumentation systems where there is a high probability of exposure to overloads. Voltage transients, failure of a transducer, or removal of the amplifier power supply while the signal source is connected may destroy or degrade the performance of an unprotected amplifier. Although it is impractical to protect an IC internally against connection to power lines, it is relatively easy to provide protection against typical system overloads.

The AMP01 is internally protected against overloads for gains of up to 100. At higher gains, the protection is reduced and some external measures may be required. Limited internal overload protection is used so that noise performance would not be significantly degraded.

AMP01 noise level approaches the theoretical noise floor of the input stage which would be 4 nV/ $\overline{\text{Hz}}$ at 1 kHz when the gain is set at 1000. Noise is the result of shot noise in the input devices and Johnson noise in the resistors. Resistor noise is calculated from the values of R_G (200 Ω at a gain of 1000) and the input protection resistors (250 Ω). Active loads for the input transistors contribute less than 1 nV/ $\overline{\text{Hz}}$ of noise. The measured noise level is typically 5 nV/ $\overline{\text{Hz}}$.

Diodes across the input transistor's base-emitter junctions, combined with 250 Ω input resistors and R_G , protect against differential inputs of up to ± 20 V for gains of up to 100. The diodes also prevent avalanche breakdown that would degrade the I_B and I_{OS} specifications. Decreasing the value of R_G for gains above 100 limits the maximum input overload protection to ± 10 V.

External series resistors could be added to guard against higher voltage levels at the input, but resistors alone increase the input noise and degrade the signal-to-noise ratio, especially at high gains.

Protection can also be achieved by connecting back-to-back 9.1 V Zener diodes across the differential inputs. This technique does not affect the input noise level and can be used down to a gain of 2 with minimal increase in input current. Although voltage-clamping elements look like short circuits at the limiting voltage, the majority of signal sources provide less than 50 mA, producing power levels that are easily handled by low-power Zeners.

Simultaneous connection of the differential inputs to a low impedance signal above 10 V during normal circuit operation is unlikely. However, additional protection involves adding 100 Ω current-limiting resistors in each signal path prior to the voltage clamp, the resistors increase the input noise level to just 5.4 nV/ $\sqrt{\text{Hz}}$ (refer to Figure 35).

Input components, whether multiplexers or resistors, should be carefully selected to prevent the formation of thermocouple junctions that would degrade the input signal.

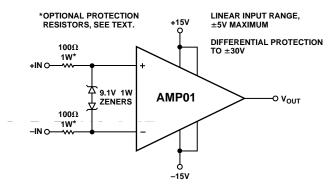


Figure 35. Input Overvoltage Protection for Gains 2 to 10,000

POWER SUPPLY CONSIDERATIONS

Achieving the rated performance of precision amplifiers in a practical circuit requires careful attention to external influences. For example, supply noise and changes in the nominal voltage directly affect the input offset voltage. A PSR of 80 dB means that a change of 100 mV on the supply, not an uncommon value, will produce a 10 μV input offset change. Consequently, care should be taken in choosing a power unit that has a low output noise level, good line and load regulation, and good temperature stability.

REV. D –15–

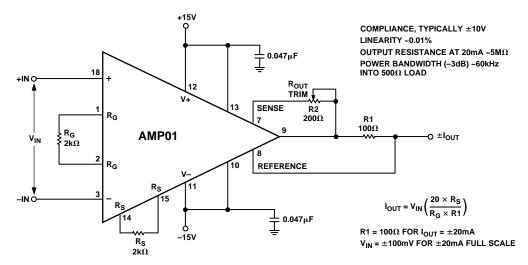


Figure 36. High Compliance Bipolar Current Source with 13-Bit Linearity

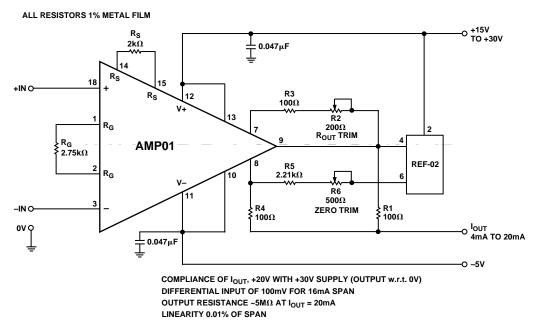


Figure 37. 13-Bit Linear 4–20 mA Transmitter Constructed by Adding a Voltage Reference. Thermocouple Signals Can Be Accepted Without Preamplification.

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REV. D

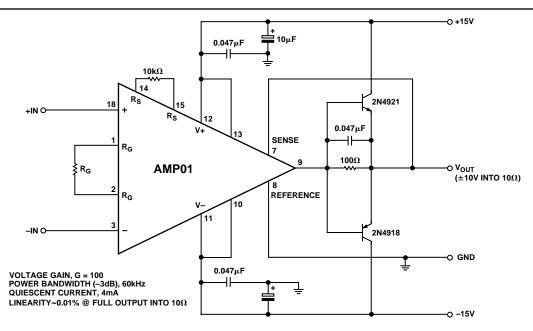


Figure 38. Adding Two Transistors Increases Output Current to ± 1 A Without Affecting the Quiescent Current of 4 mA. Power Bandwidth is 60 kHz.

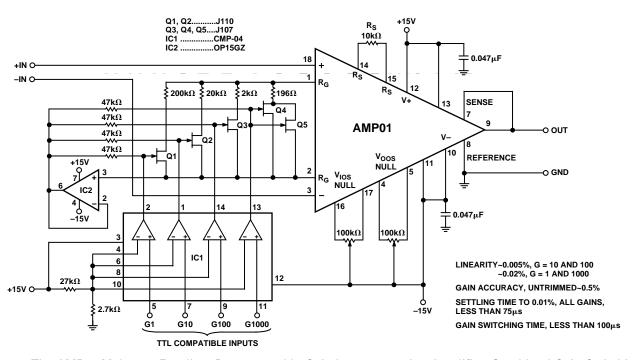


Figure 39. The AMP01 Makes an Excellent Programmable-Gain Instrumentation Amplifier. Combined Gain-Switching and Settling Time to 13 Bits Falls Below 100 μ s. Linearity Is Better than 12 Bits over a Gain Range 1 to 1000.

REV. D –17–

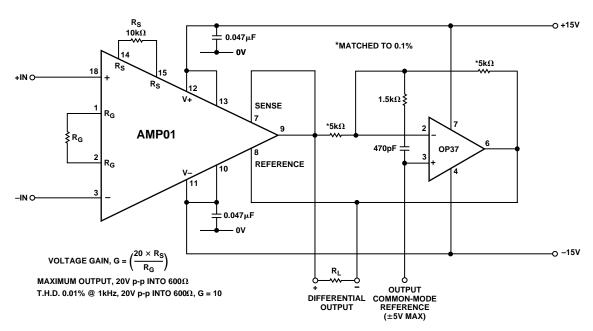


Figure 40. A Differential Input Instrumentation Amplifier with Differential Output Replaces a Transformer in Many Applications. The Output will Drive a 600 Ω Load at Low Distortion, (0.01%).

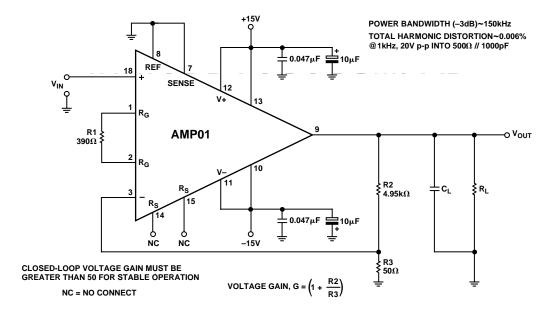


Figure 41. Configuring the AMP01 as a Noninverting Operational Amplifier Provides Exceptional Performance. The Output Handles Low Load Impedances at Very Low Distortion, 0.006%.

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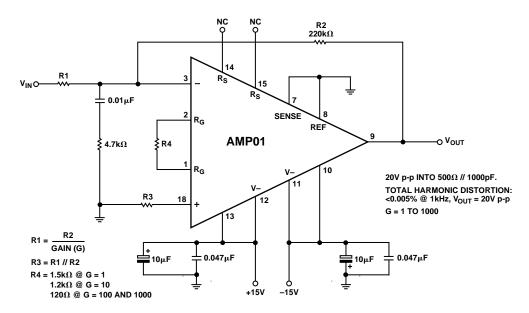


Figure 42. The Inverting Operational Amplifier Configuration has Excellent Linearity over the Gain Range 1 to 1000, Typically 0.005%. Offset Voltage Drift at Unity Gain Is Improved over the Drift in the Instrumentation Amplifier Configuration.

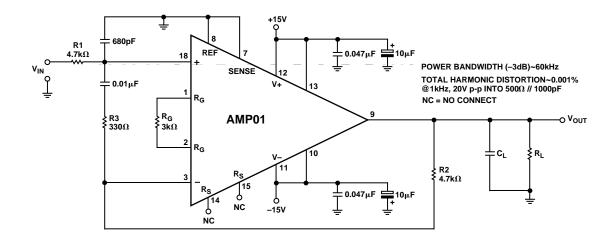


Figure 43. Stability with Large Capacitive Loads Combined with High Output Current Capability make the AMP01 Ideal for Line Driving Applications. Offset Voltage Drift Approaches the TCV_{IOS} Limit, (0.3 μ V/°C).

REV. D –19–

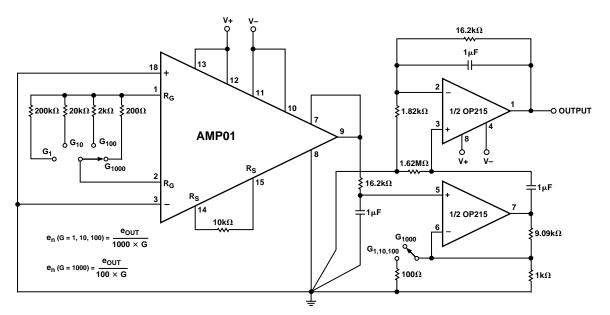


Figure 44. Noise Test Circuit (0.1 Hz to 10 Hz)

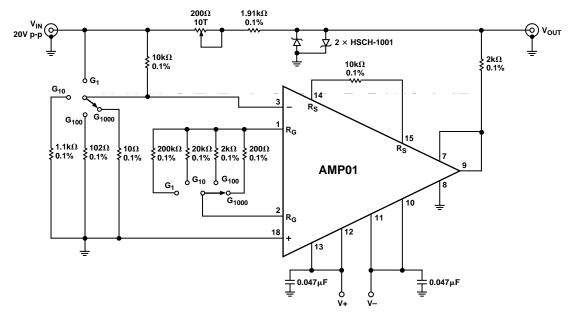


Figure 45. Settling-Time Test Circuit

-20- REV. D

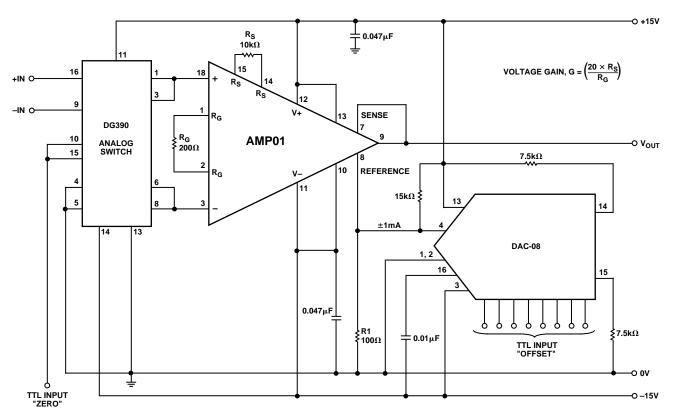


Figure 46. Instrumentation Amplifier with Autozero

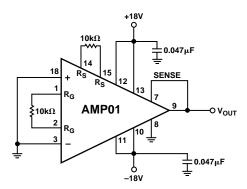


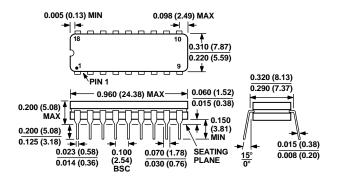
Figure 47. Burn-In Circuit

REV. D –21–

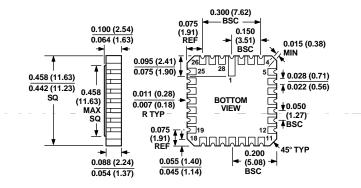
OUTLINE DIMENSIONS

Dimensions shown in inches and (mm).

18-Lead Cerdip (Q-18)



28-Terminal Ceramic Leadless Chip Carrier (E-28A)



20-Lead SOIC (R-20)

